

ZEISS Versa X-ray Microscope Offerings



ZEISS Versa 3D X-ray microscopes support a broad spectrum of users across multiple fields at academic institutions, government research labs, industrial research and development, and manufacturing sites. These instruments expand the horizons of what researchers can learn about their samples. The most highly adopted X-ray microscope platform in the world is now available with greater flexibility in system configuration and software support to help you solve the challenges that change daily and to meet new opportunities head-on.

ZEISS Versa 3D X-ray Microscope Family

Features	VersaXRM 730	VersaXRM 615	515 Versa
Sealed Transmission, Fast Activation Source	30-160 kV, 25 W	30-160 kV, 25 W	30-160 kV, 10 W
Spatial Resolution ^[a]	450 nm	500 nm	500 nm
Resolution Performance ^[b]	500 nm		
Resolution Performance at a Distance ^[c]	700 nm @ 50 mm, 750 nm @ 100 mm		
Resolution at a Distance (RaAD) ^[c]		1.0 µm @ 50 mm	1.0 µm @ 50 mm
Highest Resolution Detector (optional)	40x-P	40x	40x
Control System	ZEN navx Navigation & Guidance	ZEN navx Navigation & Guidance	Scout-and-Scan
Filter Holder	Automated Filter Changer	Manual	Manual
On-system Viewer	3D View ZEISS edition	3D View ZEISS edition	TXM 3DViewer
Sample and Instrument Protection	SmartShield, SmartShield Lite	SmartShield, SmartShield Lite	SmartShield
Flat Panel Extension (FPX)	Optional	Optional	Optional
FAST Mode	Enabled; FPX required	Enabled; FPX required	
Autoloader	Optional	Optional	Optional
<i>In situ</i> Interface Kit	Optional	Optional	Optional
Advanced Features	WFM 4X, HART, DSCoVer		
Diffraction Contrast Tomography	Optional		
Advanced Reconstruction Toolbox			
High-performance Workstation	Included	Included	Optional
DeepRecon Pro	2-year license Included	2-year license Included	1-year or Perpetual license Optional
DeepScout	Optional	Optional	Optional
MARS	Optional	Optional	Optional
PhaseEvolve	Optional	Optional	Optional
OptiRecon	Optional	Optional	Optional
ART Packages			
AI Supercharger	Upgrade	Upgrade	Optional
Recon Package	Upgrade	Upgrade	Optional
Artifact Reduction Package	Optional	Optional	Optional
ART Premium	Upgrade	Upgrade	Optional

[a] Spatial resolution measured with ZEISS XRM 2D resolution target, normal field mode, optional 40x-P (730) or 40x (615, 515).

[b] Resolution performance measured with ZEISS XRM 2D resolution target, normal field mode, optional 40x-P objective.

[c] RaAD working distance is defined as clearance around axis of rotation (sample radius). Resolution is measured with ZEISS 2D resolution target.



Seeing beyond

Versa: The World's Most Proven X-ray Microscope

42+

Countries publishing Versa XRM papers

3

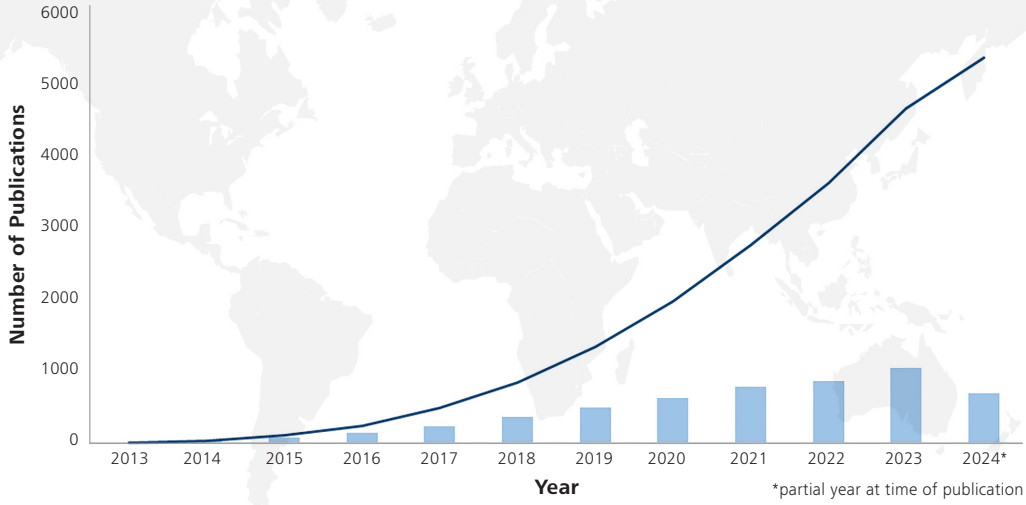
On average, new ZEISS Versa XRM publications *every day*

6000

Versa XRM publications *and counting...*

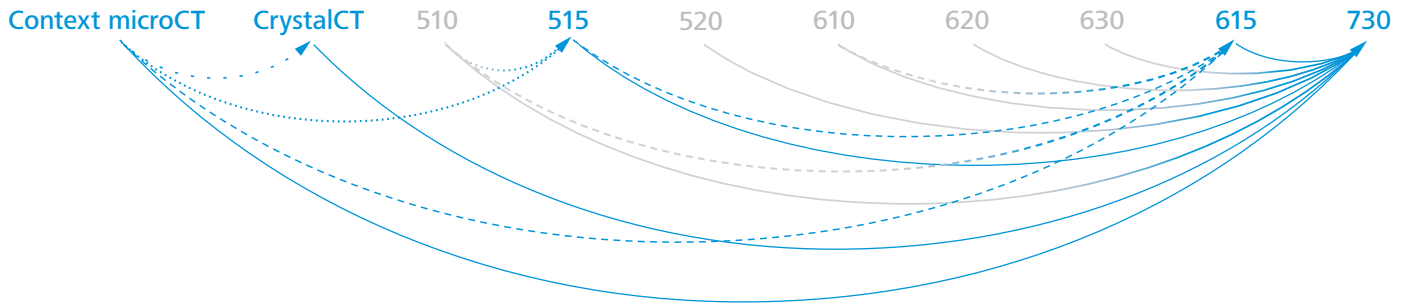
400+

Unique institutions listed as authors or co-authors



Protect Your Investment

ZEISS X-ray microscopes are designed to be upgradeable and extendable to future innovations and developments so that your initial investment is protected. This ensures your microscope capabilities evolve with the advancements in leading technology, a key differentiator in the 3D X-ray imaging industry.



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